

# *The Next Generation* Materials for SRF Cavities

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# Outline

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1. General motivation.
2. Technological motivation & S-I-S structures.
3. The project SMART & LOT, USiegen
4. The experimental set-up & the deposition technique (DCMS).
5. Results & Discussions.
6. Next steps.

# General motivation: S&T Advancement

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**Q.** What are **the scientific and technological impacts** of **R&D endeavors** for particle accelerators?

**...at cosmic scales: e.g., the study of dark matter in relation to the Standard Model.**

**...at atomic scales: e.g., the real-time imaging and measurement of structural and electronic dynamics at the quantum scale → the workings of matter at the quantum scale.**

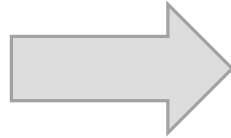
**...new possibilities and capabilities** beyond those existing currently so as to allow us to address fundamental scientific questions while contributing to the technological advancement in favor of societies.

# Technology-specific motivation

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## The Challenge

The bottleneck set by bulk niobium.



## The possible solution(s)

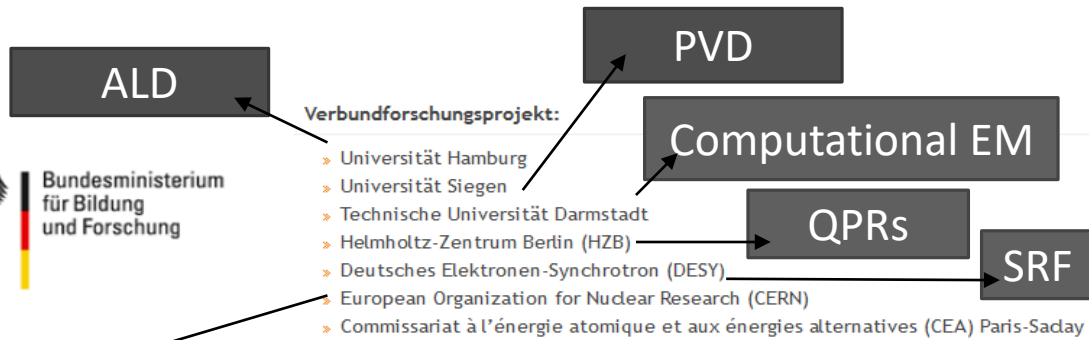
Advanced material structures: mono- and/or multi-layer (S-I-S) structured superconducting thin films (TFs).

*“Optimized multilayers of Nb<sub>3</sub>Sn, NbN, some of the iron pnictides, or alloyed Nb deposited onto the surface of the Nb resonator cavities could potentially double **the rf breakdown field**, pushing **the peak accelerating electric fields** above **100 MV/m** while protecting the cavity from **dendritic thermomagnetic avalanches** caused by **local penetration of vortices**.”* [AIP Advances 5, 017112 (2015)]

# The Project SMART & LOT- USiegen



**SIS Multilayer Structures for Applications in Superconducting Radio-Frequency Technology (SMART)** [<https://www.mb.uni-siegen.de/lot/forschung/projekte/smart.html?lang=de>]



Additional expertise, in particular in QPRs

Additional expertise in (ALD)-based ML TFs

- Thermal CVD
- MWCVD
- ECRMWCVD
- HFCVD
- **DCMS, HiPIMS**
- **RFMS**
- Electroplating

**Some available in-house know-how.**



Coatings Technology
<b>Group leader</b> Michael Vogel
Superhard materials
'Sensing' materials
Superconductive thin films
Thin films for particle accelerators
TCO thin films
Photoelectron emission materials

Management
<b>Head</b> Prof. Dr. Xin Jiang
<b>Deputy</b> Dr. Thorsten Staedler
<b>Secretary</b> Andrea Brombach

Nanomaterials
<b>Group leader</b> Dr. Yang Nianjun
Metal oxide nanowires
DNA nanosensors
Energy storage and conversion
Catalyst for sustainable chemistry

Materials Characterization
<b>Group leader</b> Dr. Thorsten Staedler
Failure analysis
High resolution direct imaging of surface morphology and cross-sections
Structural analysis
Elemental mapping and depth profiling
Mechanical and tribological materials characterization down to the nanometer regime

- ALD: Atomic Layer Deposition
- PVD: Physical Vapor Deposition
- QPR: Quadrupole Resonator

[<https://www.mb.uni-siegen.de/lot/lehrstuhl/organisation/?lang=de>]

# The Objectives of LOT, UniSiegen in the Project SMART

**Systematic investigations of surface properties of novel materials – formed by coating of mono- or multi-layers of varying:**

**Composition (e.g., Nb, Nb(Ti)N, Nb<sub>3</sub>Sn, AlN, etc.)**

**Thickness (multilayer S-I-S).**

## KEY CHALLENGES

**Materials:** Stoichiometric films with low defect density for high crystalline quality.

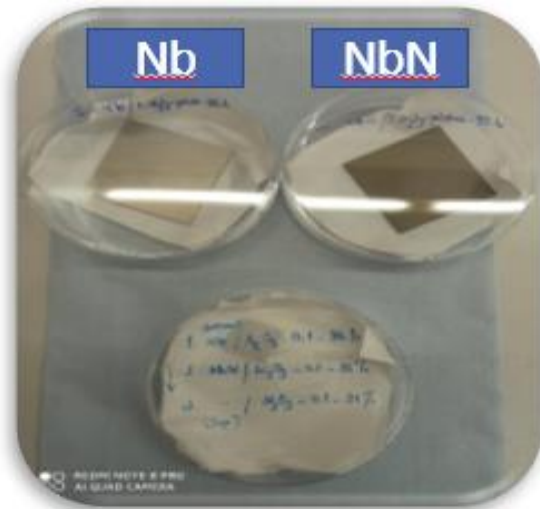
**Coating Processes:** Up-scaling capacity.



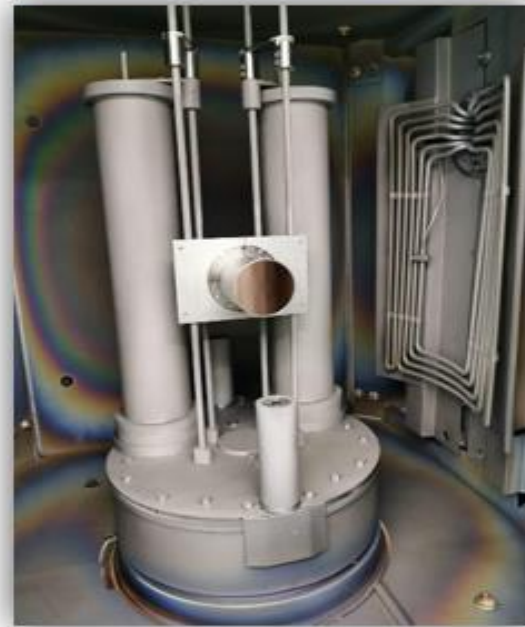
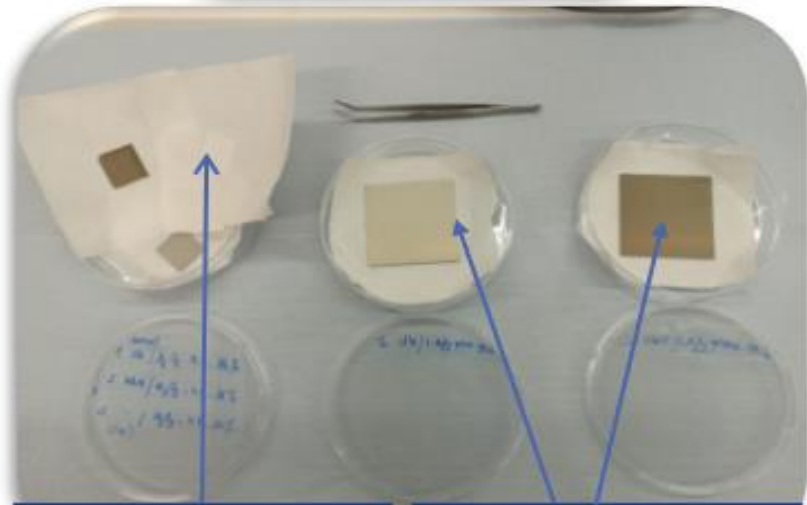
**Optimization studies to determine feasible deposition parameters:**

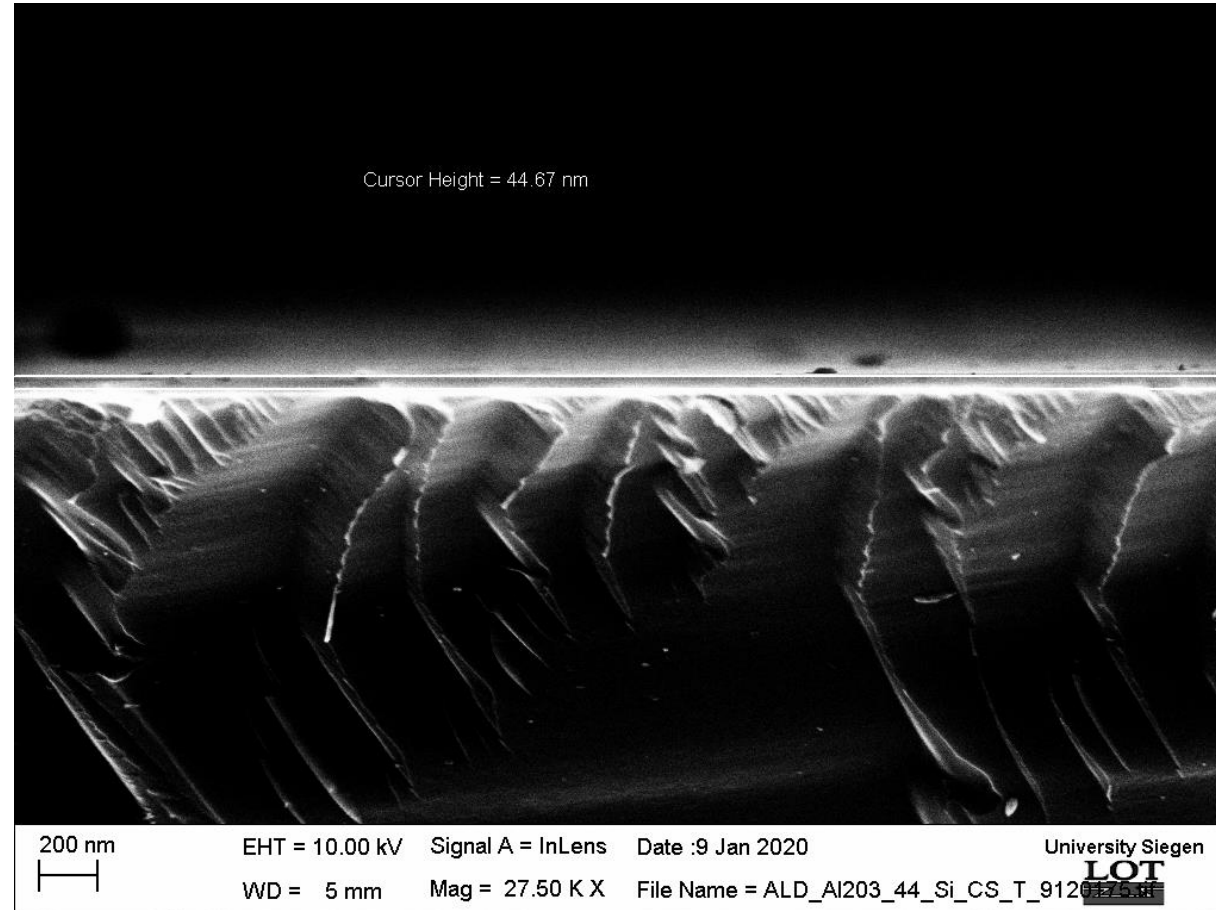
- Cathode Power,
- Gas pressure,
- Target/substrate materials,
- Substrate temperature,
- Substrate bias,
- Process gas.

# Experimental Set-up



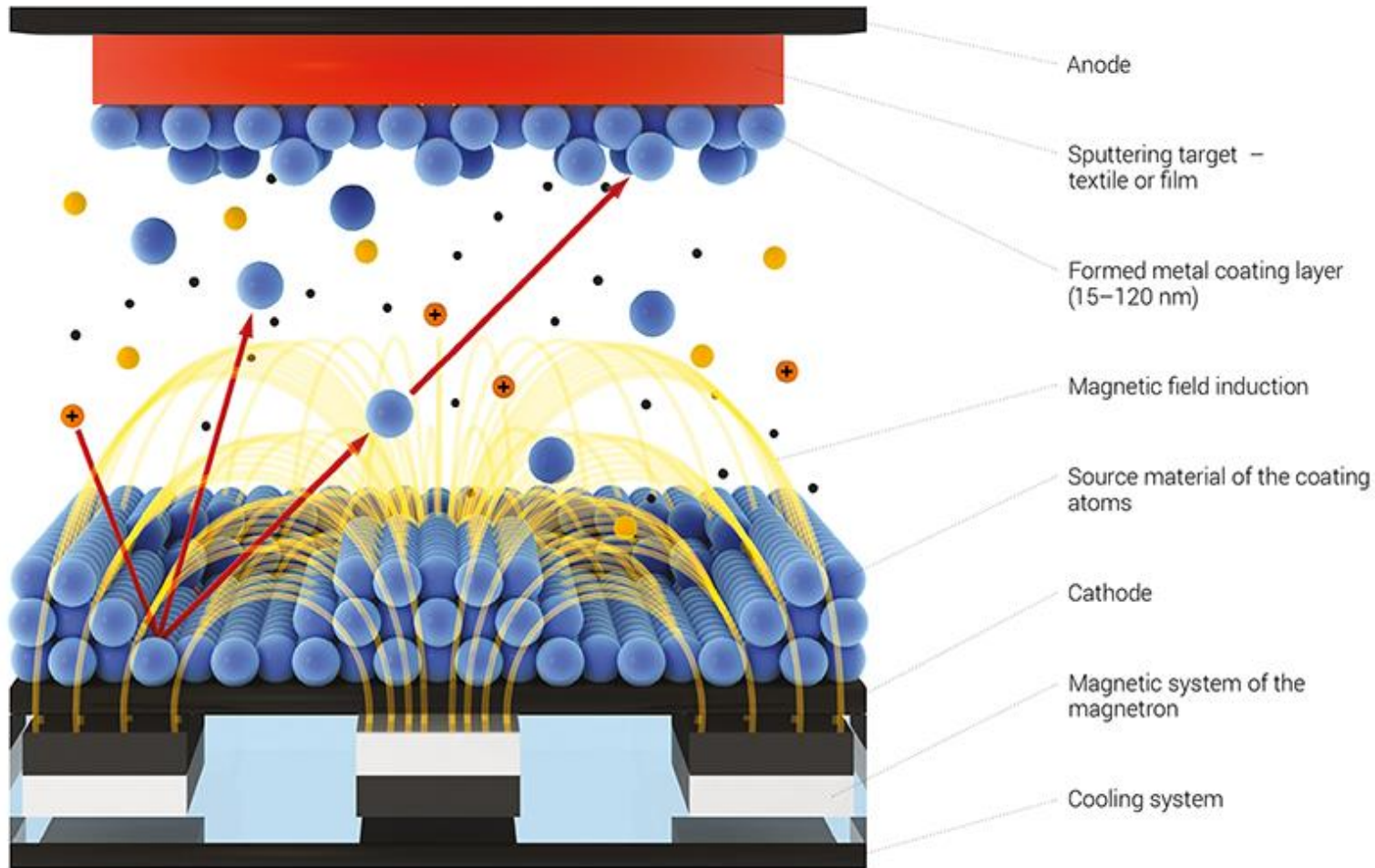
Target: Nb  
(RRR300)  
(100\*88\*10mm<sup>3</sup>)







# Direct Current Magnetron Sputtering (DCMS)



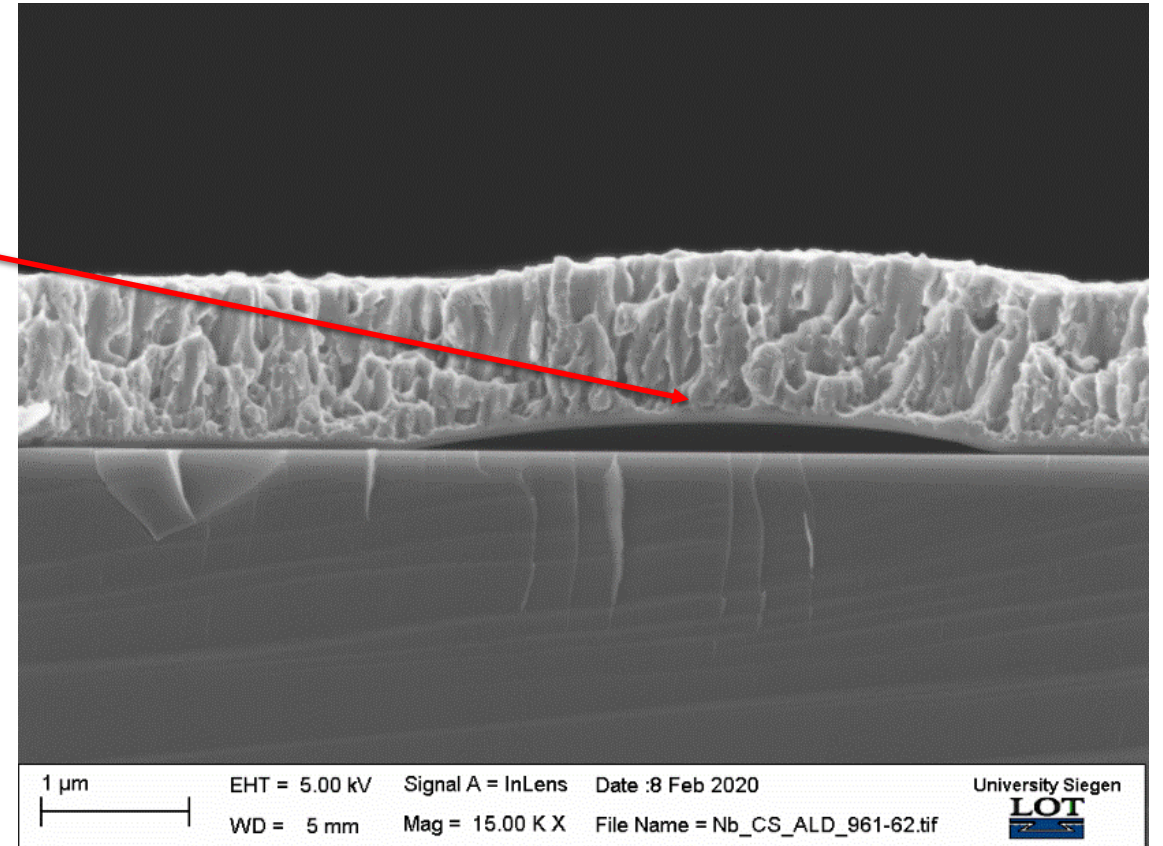
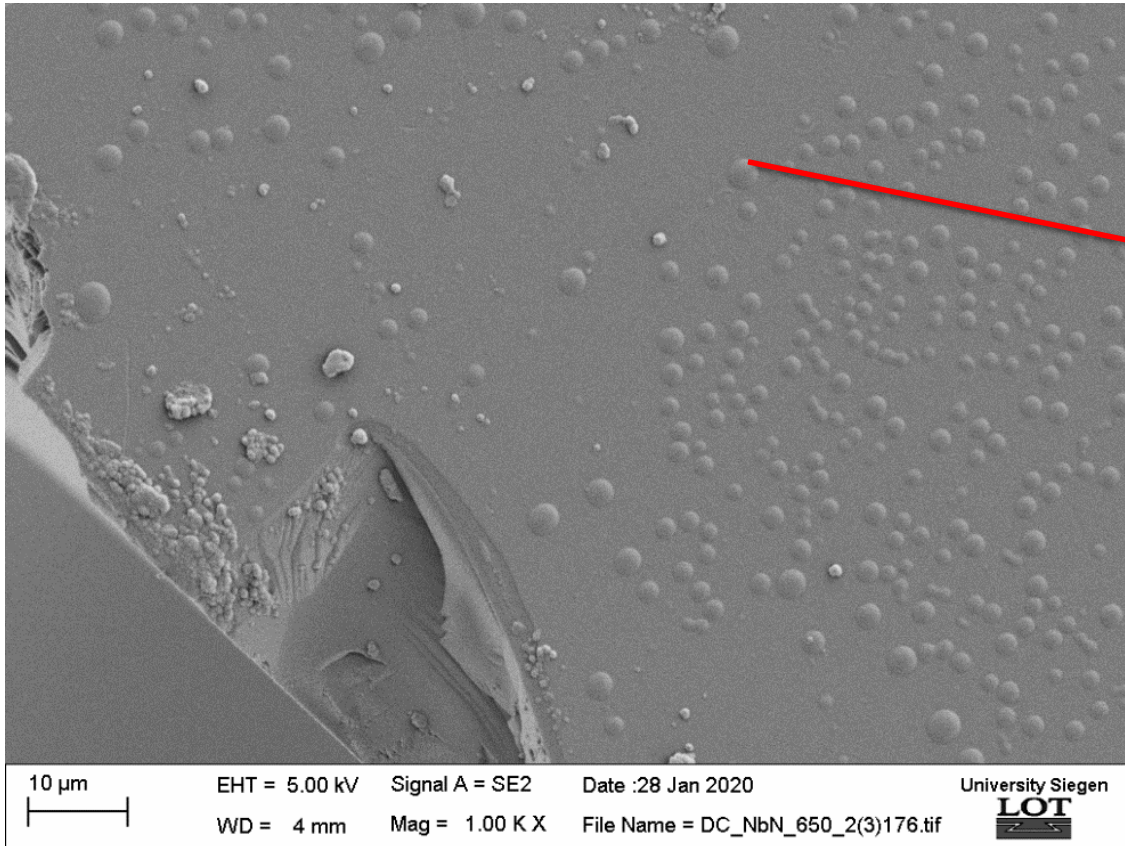
Process	Substrate Temperature T [°C]	Process Gas Pressure p[mPa]	Process Gas	Process Gas Mass Flow Rate [sccm]	Cathode Power [W]	Substrate Bias [V]	Coating Time t <sub>c</sub> [min]
1. 964	650	1200	Ar / N <sub>2</sub>	500 / 43	400	0	30



**CemeCon  
CC800**

[<https://www.visual-science.com/projects/magnetron-sputtering/technical-illustration/>]

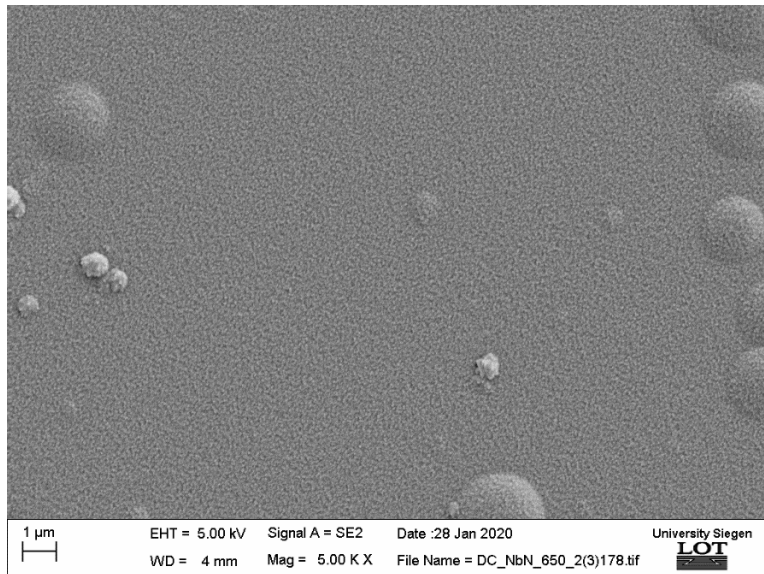
# Results & Discussions



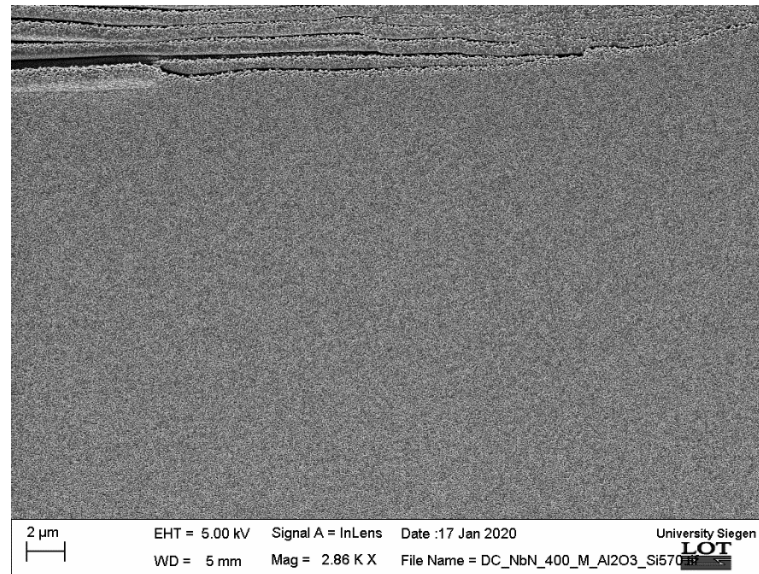


# Results & Discussions

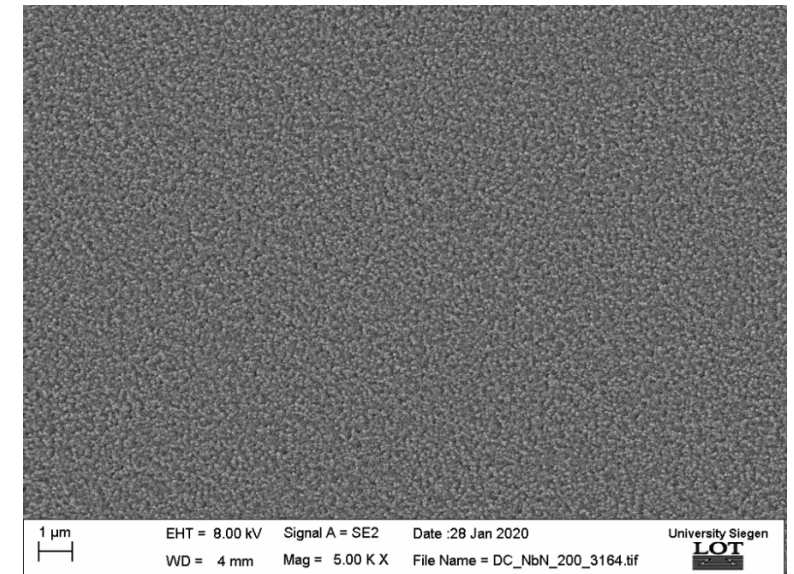
**T650**



**T400**

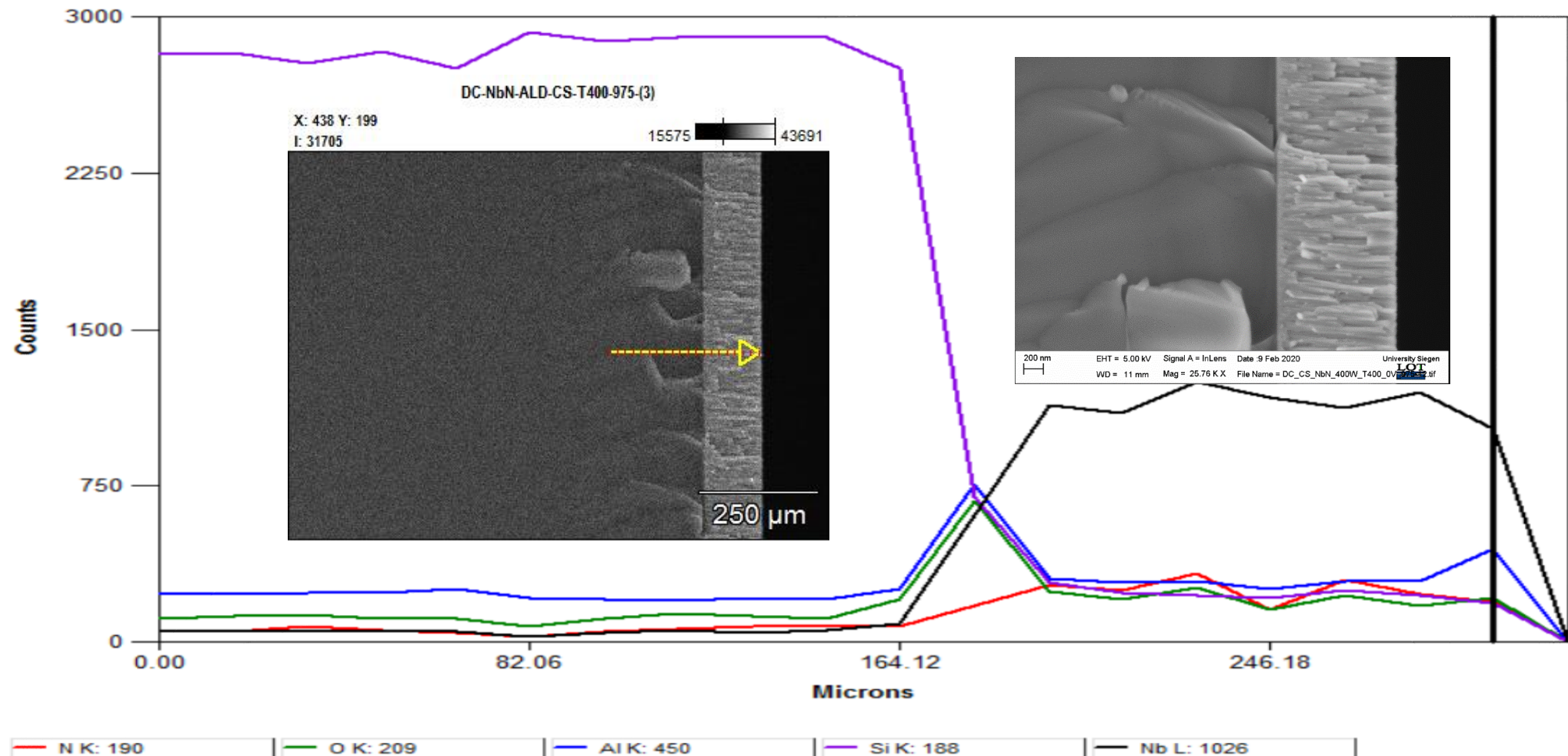


**T200**

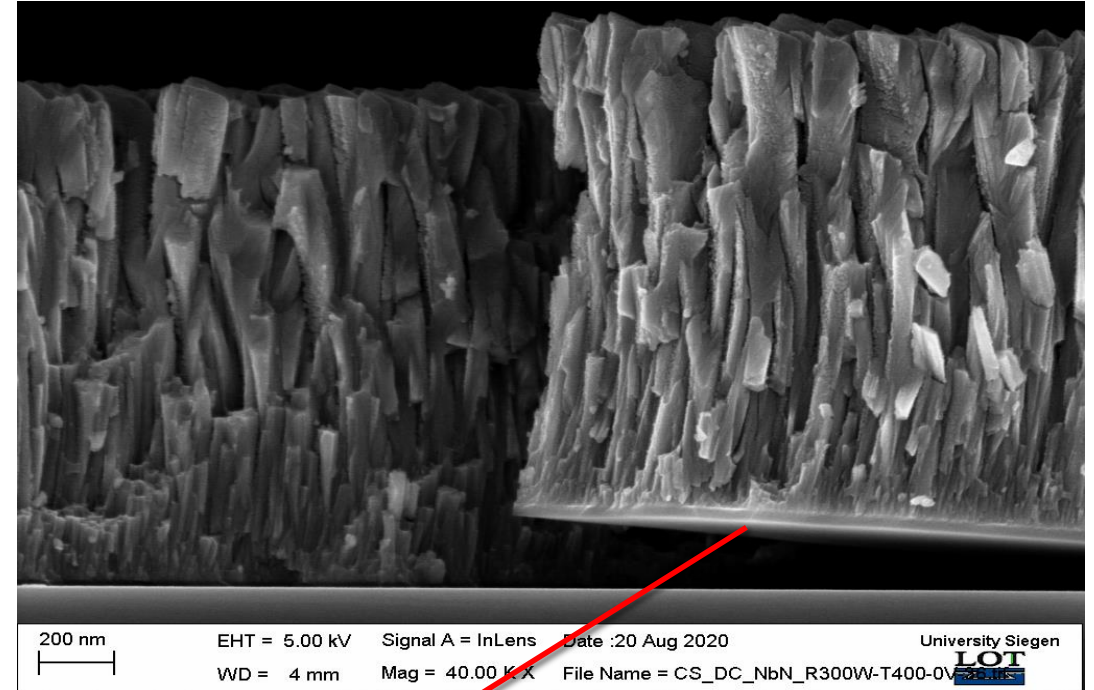
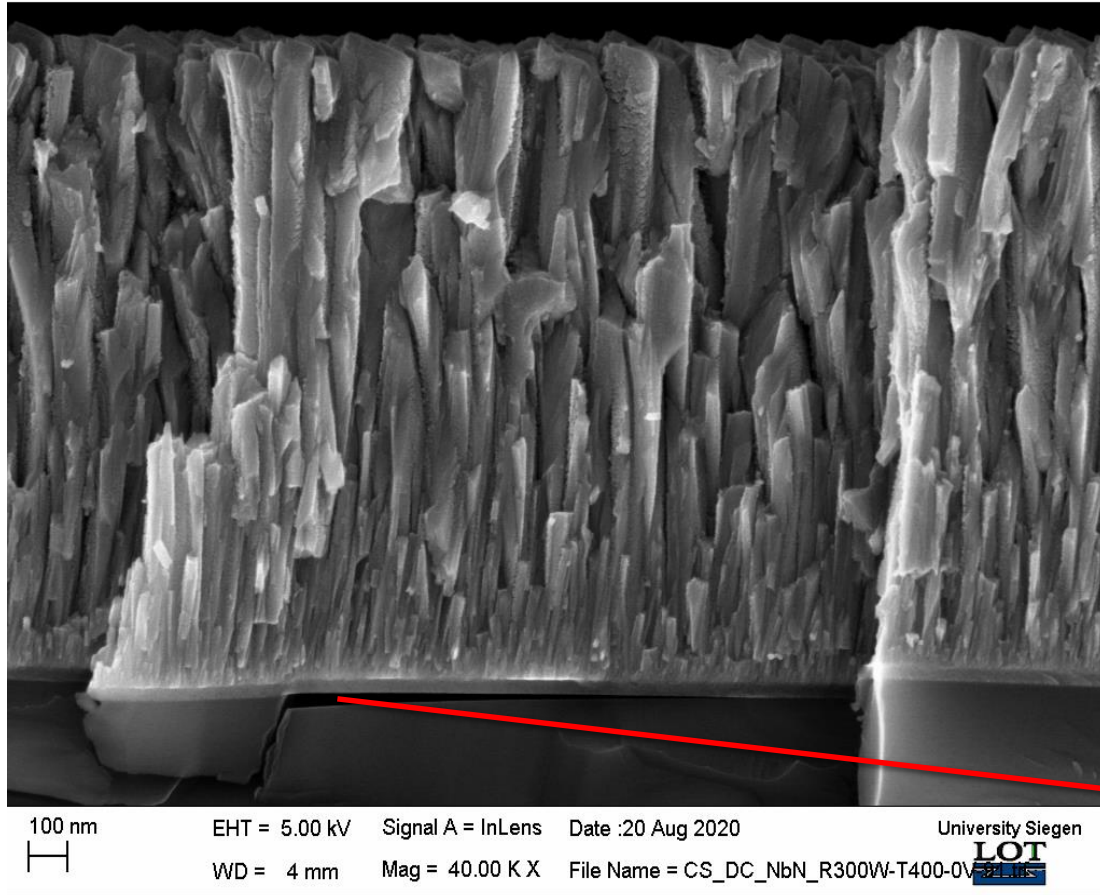


# Results & Discussions

## DC-NbN-ALD-CS-T400-975-(3)

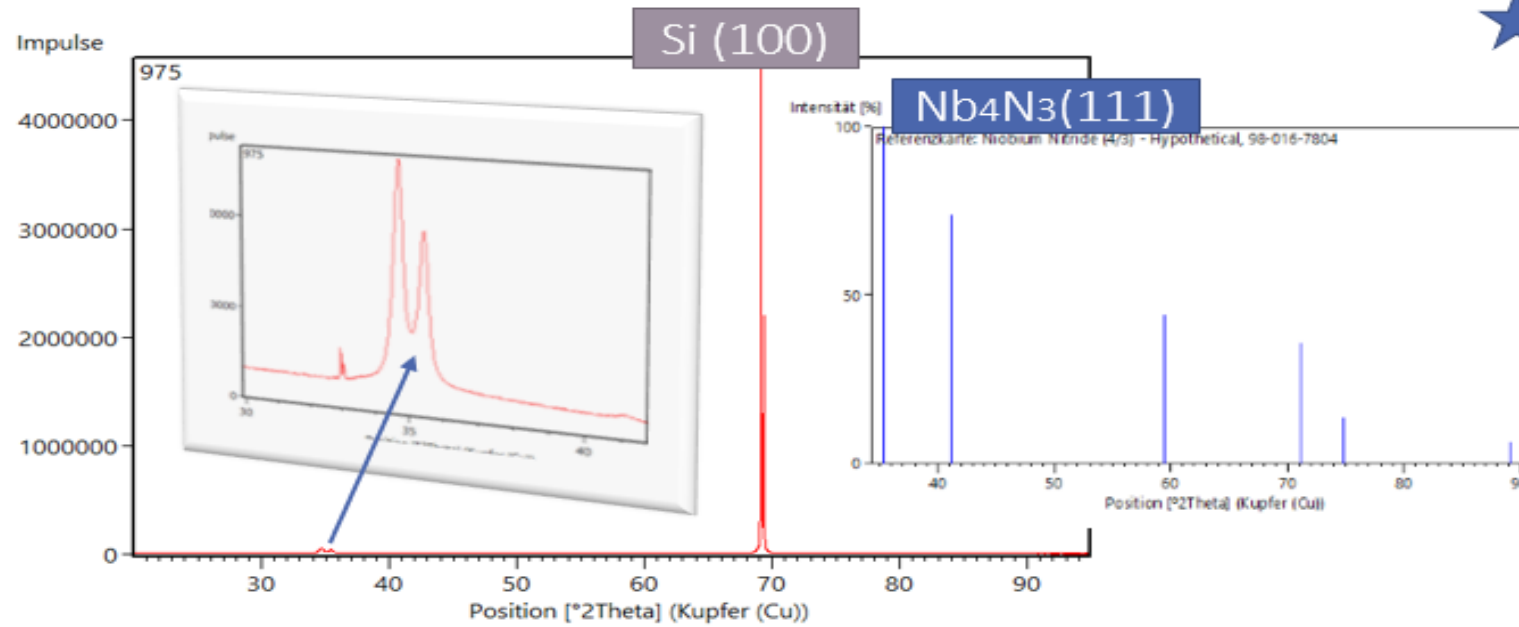


# Results & Discussions



The delamination of the insulating layer (alumina).

# Results & Discussions



## ★ NbN

- $T_c = 17.3\text{K}$
- $H_c = 230\text{mT}$   
(wrt Nb,  $H_c = 200\text{mT}$ )

## Superconducting NbN Phases:

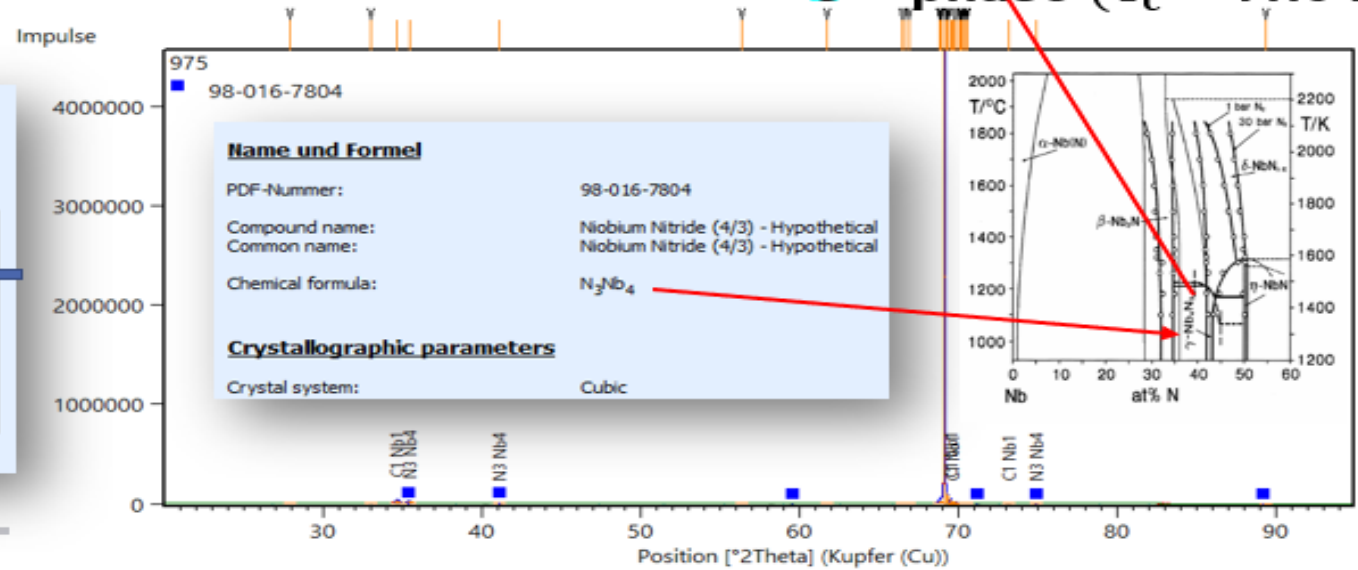
★ **γ** – phase ( $\text{Nb}_4\text{N}_3$ )  
( $T_c = 12 - 15\text{K}$ )

• **δ** – phase ( $\text{NbN}_x$ )  
( $T_c = 15 - 17.3\text{K}$ )

• **ε** – phase ( $T_c \sim 11.6\text{K}$ )

### Peak list

No.	h	k	l	d [Å]	2θ [°]	I [%]
1	1	1	1	2,53457	35,386	100,0
2	0	0	2	2,19500	41,089	73,7
3	0	2	2	1,55210	59,510	44,2
4	1	1	3	1,32363	71,177	35,7
5	2	2	2	1,26728	74,866	13,9
6	0	0	4	1,09750	89,154	6,6



**Name und Formel**

PDF-Nummer: 98-016-7804

Compound name: Niobium Nitride (4/3) - Hypothetical  
Common name: Niobium Nitride (4/3) - Hypothetical

Chemical formula:  $\text{N}_3\text{Nb}_4$

**Crystallographic parameters**

Crystal system: Cubic



# Next Steps

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**\* The on-going experimental design of deposition processes regarding:**

§ mono-layer and / or

§ multi-layer (S-I-S) structured superconducting materials

...based on Nb(Ti)N, Nb<sub>3</sub>Sn TFs on ALD-alumina / Si and niobium substrates with various deposition techniques (e.g., DCMS, HiPIMS, RFMS etc.),

**\* Further material (surface & interfacial) characterizations (e.g., SEM /EDX, XRD, AFM, TEM, SIMS, EBSD etc.),**

**\* The thickness studies of the coated-layers (e.g., uniformity, (U)TFs),**

**\* Superconductivity characterizations (e.g., T<sub>c</sub>[K], B<sub>en</sub>[Oe], etc.).**



\* UTFs: Ultra-thin films

The on-going construction of the RF box-coater:



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**THANK YOU**

**FOR**

**YOUR ATTENTION !**

If there is any further curiosity, please feel free to contact via  
[oezdem.sezgin@uni-siegen.de](mailto:oezdem.sezgin@uni-siegen.de)